Notice of References Cited

Application/Control No. 10/541,994	Reexamination	Applicant(s)/Patent Under Reexamination HEIDE, PATRIC		
Examiner	Art Unit			
Shelley Chen	3662	Page 1 of 1		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-3,454,945 A	07-1969	HYLTIN TOM M	327/119
*	• В	US-4,637,068 A	01-1987	·Crossley et al.	455/327
*	С	US-4,901,084 A	02-1990	. Huguenin et al.	342/179
*	D	US-4,910,523 A	03-1990	Huguenin et al.	342/179
*	E	US-5,073,782 A	12-1991	Huguenin et al.	342/179
*	F	US-5,202,692 A	04-1993	Huguenin et al.	342/179
*	G	US-5,227,800 A	07-1993	Huguenin et al.	342/179
*	Н	US-5,675,295 A	10-1997	Brebels et al.	331/105
*	ı	US-6,091,355 A	07-2000	Cadotte et al.	342/104
*	J	US-2006/0097906 A1	05-2006	Heide, Patric	342/022
	к	US-			
	L	US-	T == ==		
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYY.Y	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R				·	
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition of	or Volume, Pertinent Pages)
	υ		
	v		
	w		
	x		

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classif ications may be US or foreign.